









SN74HC573A-Q1 SCLS600C - NOVEMBER 2004 - REVISED JUNE 2022

# SN74HC573A-Q1 Octal Transparent D-Type Latch With 3-State Outputs

#### 1 Features

- Qualified for automotive applications
- Wide operating voltage range of 2 V to 6 V
- High-current 3-state outputs drive bus lines directly or up to 15 LSTTL loads
- Low power consumption, 80-µA max I<sub>CC</sub>
- Typical  $t_{pd}$  = 21 ns
- ±6-mA output drive at 5 V
- Low input current of 1 µA max
- **Bus-structured pinout**

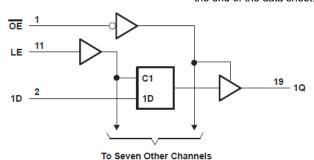
### 2 Description

This octal transparent D-type latch features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

#### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)		
SN74HC573AQDW-Q1	SOIC (20)	12.80 mm × 7.50 mm		
SN74HC573AQPW-Q1	TSSOP (20)	6.50 mm × 4.40 mm		

For all available packages, see the orderable addendum at the end of the data sheet.



**Functional Block Diagram** 



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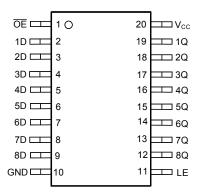
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<b>3 Revision History</b> NOTE: Page numbers for previous revisions may	differ fı	rom page numbers in the current version.	
Changes from Revision B (February 2022) to R	levisio	n C (June 2022)	Page
Junction-to-ambient thermal resistance values		sed. DW was 58 is now 109.1, PW was 83 is r	
Changes from Povision A (April 2008) to Povis	ion B	/Fobruary 2022\	Page

Changes from Revision A (April 2008) to Revision B (February 2022)

Page



# **4 Pin Configuration and Functions**



DW or PW Package 20-Pin SOIC or TSSOP Top View



# **5 Specifications**

# 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		·	MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_I < 0$ or $V_I > V_{CC}$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$		±35	mA
	Continuous current through V <sub>CC</sub> or GND			±70	mA
TJ	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# 5.2 Recommended Operating Conditions<sup>(1)</sup>

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			V
		V <sub>CC</sub> = 6 V	4.2			
		V <sub>CC</sub> = 2 V			0.5	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35	V
		V <sub>CC</sub> = 6 V			1.8	
VI	Input voltage		0		V <sub>CC</sub>	V
V <sub>O</sub>	Output voltage		0		V <sub>CC</sub>	V
		V <sub>CC</sub> = 2 V			1000	
t <sub>t</sub>	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V			500	ns
		V <sub>CC</sub> = 6 V			400	
T <sub>A</sub>	Operating free-air temperature	<u>'</u>	-40		125	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

#### 5.3 Thermal Information

		DW (SOIC)	PW (TSSOP)	
THERMAL ME	TRIC	20 PINS	20 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)</sup>	109.1	131.8	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	76	72.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.6	82.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	51.5	21.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	77.1	82.4	°C/W
R <sub>θJC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

Product Folder Links: SN74HC573A-Q1

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### **5.4 Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V <sub>CC</sub> T <sub>A</sub> = 25°C			T <sub>A</sub> = -40°C to 125°C		T <sub>A</sub> = -40°C to 85°C		UNIT		
				MIN	TYP	MAX	MIN	MAX	MIN	MAX		
			2 V	1.9	1.998		1.9		1.9			
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4			
$V_{OH}$	$V_I = V_{IH}$ or $V_{IL}$	L	6 V	5.9	5.999		5.9		5.9		V	
		I <sub>OH</sub> = −6 mA	4.5 V	3.98	4.3		3.7		3.84			
		I <sub>OH</sub> = -7.8 mA	6 V	5.48	5.8		5.2		5.34			
	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>			2 V		0.002	0.1		0.1		0.1	
		$I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1		0.1		
$V_{OL}$			6 V		0.001	0.1		0.1		0.1	V	
		I <sub>OL</sub> = 6 mA	4.5 V		0.17	0.26		0.4		0.33		
		I <sub>OL</sub> = 7.8 mA	6 V		0.15	0.26		0.4		0.33		
I <sub>I</sub>	$V_I = V_{CC}$ or 0	•	6 V		±0.1	±100		±1000		±1000	nA	
l <sub>OZ</sub>	V <sub>O</sub> = V <sub>CC</sub> or 0		6 V		±0.01	±0.5		±10		±5	μA	
I <sub>CC</sub>	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6V			8		160		80	μΑ	
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF	

# 5.5 Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted)

			T <sub>A</sub> = 25°C	T <sub>A</sub> = -40°C to 125°C	T <sub>A</sub> = -40°C to 85°C	UNIT
		V <sub>cc</sub>	MIN MAX	MIN MAX	MIN MAX	ONII
	Pulse duration, LE high	2 V	80	120	100	
t <sub>w</sub>		4.5 V	16	24	20	ns
		6 V	14	20	17	
	Setup time, data before LE↓	2 V	50	75	63	
t <sub>su</sub>		4.5 V	10	15	13	ns
		6 V	9	13	11	
		2 V	20	24	24	
t <sub>h</sub>	Hold time, data after LE ↓	, data after LE ↓ 4.5 V	5	5	5	ns
		6 V	5	5	5	



# **5.6 Switching Characteristics**

over recommended operating free-air temperature range,  $C_L$  = 50 pF (unless otherwise noted) (see Figure 6-1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>		= 25°C		T <sub>A</sub> = -40°C to 125°C	0	T <sub>A</sub> = -40°C to 85°C	UNIT		
	(INPUT)	(INPUT)	(OUTPUT)		MIN	TYP	MAX	MIN N	IAX	MIN MAX		
			2 V		77	175	:	265	220			
	D	Q	4.5 V		26	35		53	44			
			6 V		23	30		45	38	20		
t <sub>pd</sub>			2 V		87	175		265	260	ns		
	LE	LE /	LE	Any Q	4.5 V		27	35		53	44	
						6 V		23	30		45	38
			2 V		68	150		225	190			
t <sub>en</sub>	ŌĒ	Any Q	4.5 V		24	30		45	38	ns		
			6 V		21	26		38	32			
			2 V		47	150		225	190			
t <sub>dis</sub>	ŌĒ	Any Q	4.5 V		23	30		45	38	ns		
			6 V		21	26		38	32	1		
			2 V		28	60		90	75			
t <sub>t</sub>		Any Q	4.5 V		8	12		18	15	ns		
			6 V		6	10		15	13			

# **5.7 Switching Characteristics**

over recommended operating free-air temperature range,  $C_L$  = 150 pF (unless otherwise noted) (see Figure 6-1)

PARAMETER	FROM TO (INPUT)		V <sub>cc</sub>	V <sub>CC</sub> T <sub>A</sub> = 25°C		T <sub>A</sub> = -40°C to 125°C	T <sub>A</sub> = -40°C to 85°C	UNIT		
	(IIVF O I)	(0011-01)		MIN	TYP	MAX	MIN MA	X MIN MA	X	
			2 V		95	200	30	00 2	50	
	D	Q	4.5 V		33	40	(	60	50	
			6 V		21	34	!	51	13 ns	
t <sub>pd</sub>	LE A	LE		2 V		103	225	3:	35 2	35
			LE	Any Q	4.5 V		33	45	(	67
			6 V		29	38		57	18	
		ŌĒ Any Q	2 V		85	200	30	00 2	50	
t <sub>en</sub>	ŌĒ		4.5 V		29	40	(	60	50 ns	
			6 V		26	34		51	13	
		2	2 V		60	210	3	5 2	35	
t <sub>t</sub>		Any Q	Any Q	4.5 V		17	42	(	33	53 ns
			6 V		14	36	,	53	15	

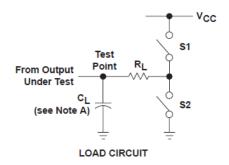
# **5.8 Operating Characteristics**

T<sub>A</sub> = 25°C

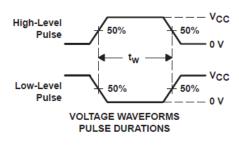
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per latch	No load	50	pF

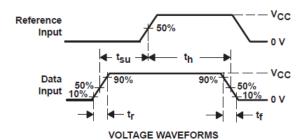
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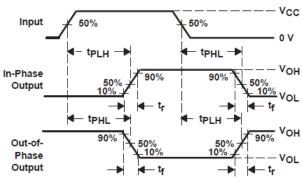
#### **6 Parameter Measurement Information**

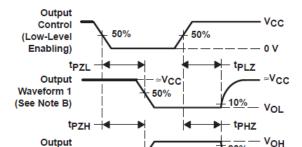


PARAI	PARAMETER		CL	S1	S2
	tPZH	1 kΩ	50 pF	Open	Closed
t <sub>en</sub>	tPZL	1 K22	or 150 pF	Closed	Open
	tPHZ			Open	Closed
<sup>t</sup> dis	t <sub>PLZ</sub>	<b>1 k</b> Ω	50 pF	Closed	Open
t <sub>pd</sub> or	t <sub>pd</sub> or t <sub>t</sub>		50 pF or 150 pF	Open	Open









SETUP AND HOLD AND INPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- A. C<sub>1</sub> includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.

Waveform 2

(See Note B)

- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_r$  = 6 ns,  $t_f$  = 6 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 6-1. Load Circuit and Voltage Waveforms

### 7 Detailed Description

#### 7.1 Overview

This octal transparent D-type latch features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

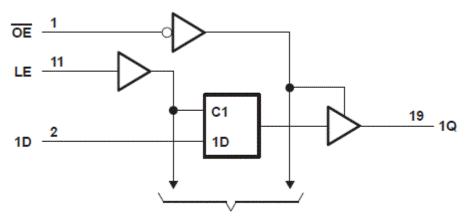
While the latch-enable (LE) input is high, the Q outputs respond to the data (D) inputs. When LE is low, the outputs are latched to retain the data that was set up.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to VCC through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

### 7.2 Functional Block Diagram



To Seven Other Channels

#### 7.3 Device Functional Modes

Table 7-1. Function Table (Each Latch)

	OUTPUT		
ŌĒ	LE	Q	
L	Н	Н	Н
L	Н	L	L
L	L	Х	$Q_0$
Н	Х	Х	Z

# 8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

### 9 Layout

#### 9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.



# 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

#### 10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 10.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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### 10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
SN74HC573AQDWRQ1	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC573AQ
SN74HC573AQDWRQ1.A	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC573AQ
SN74HC573AQPWRG4Q1	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU   NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC573AQ
SN74HC573AQPWRG4Q1.A	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC573AQ

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74HC573A-Q1:

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# PACKAGE OPTION ADDENDUM

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● Catalog : SN74HC573A

Military : SN54HC573A

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Military - QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC573AQDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.9	13.3	2.7	12.0	24.0	Q1
SN74HC573AQDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74HC573AQPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1

www.ti.com 24-Jul-2025



### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC573AQDWRQ1	SOIC	DW	20	2000	356.0	356.0	45.0
SN74HC573AQDWRQ1	SOIC	DW	20	2000	356.0	356.0	45.0
SN74HC573AQPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0



SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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